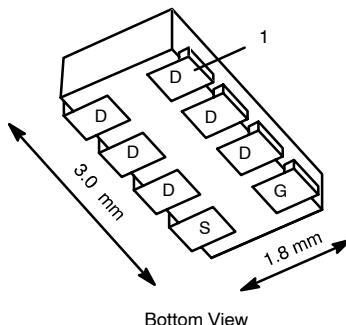


P-Channel 12-V (D-S) MOSFET

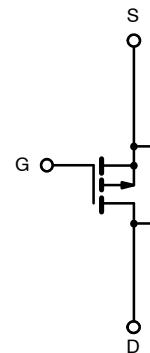
PRODUCT SUMMARY		
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A)
-12	0.031 @ $V_{GS} = -4.5$ V	-7.6
	0.041 @ $V_{GS} = -2.5$ V	-6.6
	0.054 @ $V_{GS} = -1.8$ V	-5.8

TrenchFET®
Power MOSFETs
1.8-V Rated

1206-8 ChipFET™



Marking Code
 Lot Traceability and Date Code
 Part # Code



P-Channel MOSFET

Ordering Information: Si5475DC-T1

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	5 secs	Steady State	Unit
Drain-Source Voltage	V_{DS}	-12	-5.5	V
Gate-Source Voltage	V_{GS}			
Continuous Drain Current ($T_J = 150^\circ\text{C}$) ^a	I_D	-7.6	-5.5	A
		-3.5	-3.9	
Pulsed Drain Current	I_{DM}	± 20		A
Continuous Source Current ^a	I_S	-2.1	-1.1	
Maximum Power Dissipation ^a	P_D	2.5	1.3	W
		1.3	0.7	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150		$^\circ\text{C}$
Soldering Recommendations (Peak Temperature) ^{b, c}		260		

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^a	R_{thJA}	40	50	$^\circ\text{C}/\text{W}$
		80	95	
Maximum Junction-to-Foot (Drain)	R_{thJF}	15	20	

Notes

- a. Surface Mounted on 1" x 1" FR4 Board.
- b. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- c. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

SPECIFICATIONS ($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

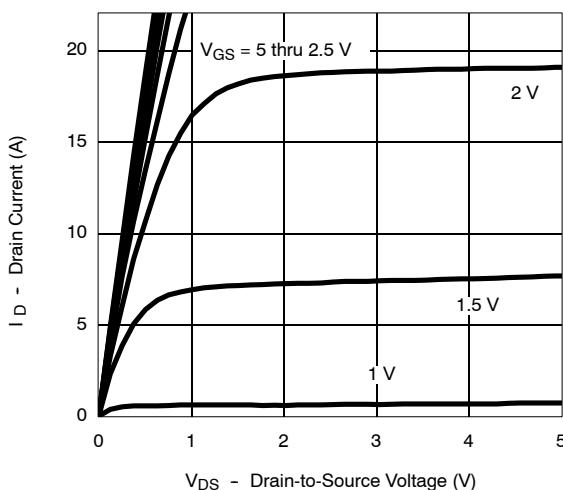
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -1 \text{ mA}$	-0.45			V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -9.6 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μA
		$V_{DS} = -9.6 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 85^\circ\text{C}$			-5	
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \leq -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	-20			A
Drain-Source On-State Resistance ^a	$r_{DS(\text{on})}$	$V_{GS} = -4.5 \text{ V}, I_D = -5.5 \text{ A}$		0.027	0.031	Ω
		$V_{GS} = -2.5 \text{ V}, I_D = -4.8 \text{ A}$		0.035	0.041	
		$V_{GS} = -1.8 \text{ V}, I_D = -2 \text{ A}$		0.045	0.054	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -5 \text{ V}, I_D = -5.2 \text{ A}$		19		S
Diode Forward Voltage ^a	V_{SD}	$I_S = -1.1 \text{ A}, V_{GS} = 0 \text{ V}$		-0.7	-1.2	V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = -6 \text{ V}, V_{GS} = -4.5 \text{ V}, I_D = -5.5 \text{ A}$		19	29	nC
Gate-Source Charge	Q_{gs}			3.9		
Gate-Drain Charge	Q_{gd}			3.6		
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = -6 \text{ V}, R_L = 6 \Omega$ $I_D \approx -1 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_G = 6 \Omega$		15	25	ns
Rise Time	t_r			20	30	
Turn-Off Delay Time	$t_{d(\text{off})}$			122	180	
Fall Time	t_f			80	120	
Source-Drain Reverse Recovery Time	t_{rr}		$I_F = -1.1 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$	40	60	

Notes

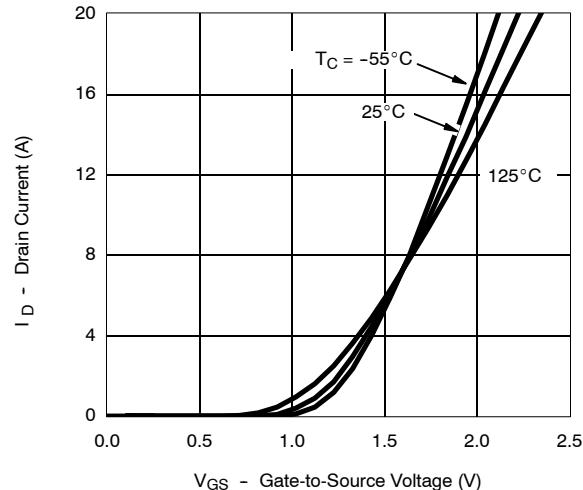
- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.

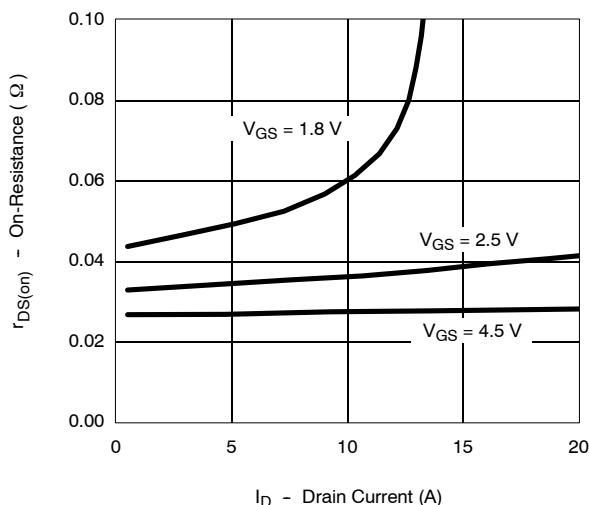
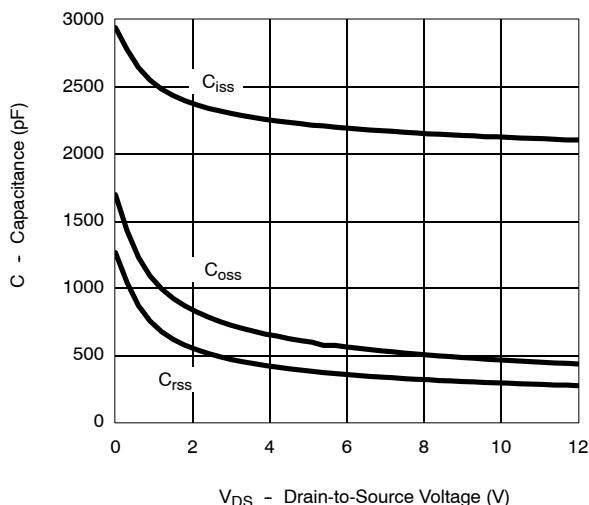
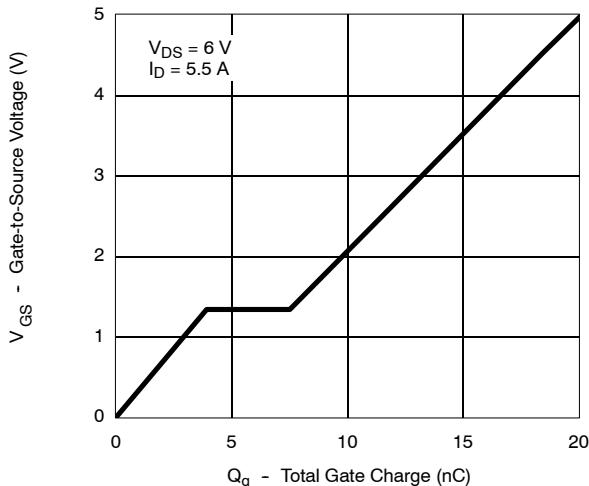
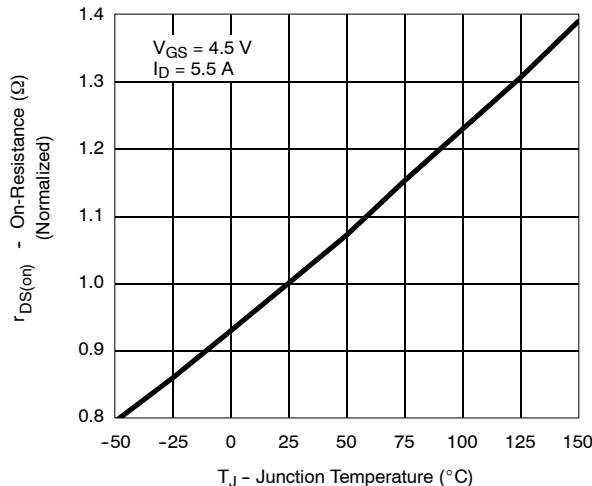
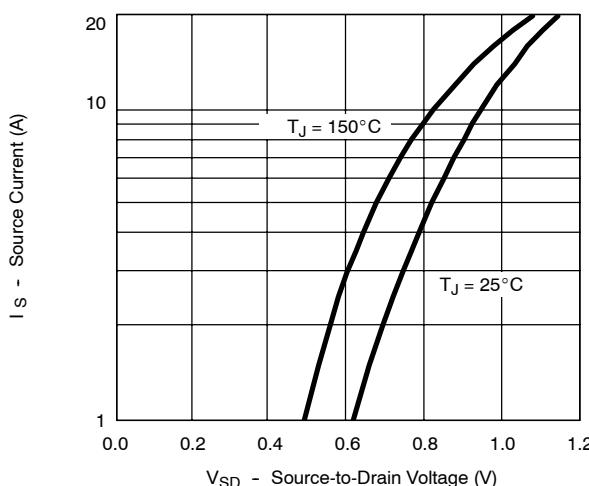
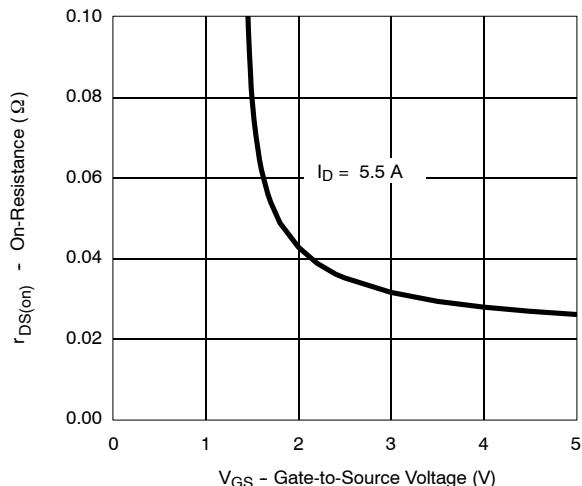
TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

Output Characteristics



Transfer Characteristics



TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)
On-Resistance vs. Drain Current

Capacitance

Gate Charge

On-Resistance vs. Junction Temperature

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage


TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

